

# Search Notes



Application/Control No.

10/089,107

Examiner

John Pezzlo

Applicant(s)/Patent under Reexamination

SANO ET AL.

Art Unit

2616

## SEARCHED

Class	Subclass	Date	Examiner
370	330, 329 208, 481 342, 335 430	2/13-16/06 JP	
375	131, 225 130, 140 142, 220- 222		
455	452		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
refer to EAST search	2/13-16/06 JP	
refer to IEEE search	2/13-15/06 JP	